

Suite 500 Chicago, Illinois USA 60631

Dec 19th, 2014

RE: PCN # ESU270-29 -- SR70-02CTG Alternate Manufacturing Location Approval for Wafer Foundry & Backend Assembly, Test and Packing

To our valued customers,

Littelfuse would like to notify you of a newly approved wafer foundry location and a backend location for the SR70-02CTG TVS Diode Array (SPA® Diodes) products. The new wafer foundry in China and the new backend factory in Philippines are all fully approved. There are no changes to fit, form, and function of the finished product.

Qualification efforts are complete and the new factories are online for immediate shipments. Please see the attached documentation for change detail and affected part numbers.

All affected products have been fully qualified in accordance with established performance and reliability criteria. The attached pages summarize the qualification results. Full qualification data and/or samples will be available upon request.

Form, fit, function changes: None Part number changes: None Effective date: Dec 19th, 2014 Replacement products: N/A

Last time buy: N/A

This notification is for your information and acknowledgement. If you have any other questions or concerns, please contact Chad Marak, Product Manager.

We value your business and look forward to assisting you whenever possible.

Best Regards,

Chad Marak

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800 E. Northwest Highway Des Plaines, IL 60016

Product/Process Change Notice (PCN)

BONE			
PCN# : ESU270-29 Date: 12/19/2014	Date: 12/19/2014 Contact Information		
Product Identification:	Name: Chad Marak		
SR70-02CTG of TVS	Title: Product Marketing Manager		
Diode Array Products	Phone #: +1 408 886 1600		
Implementation Date for Change:	Fax#: N/A		
12/19/2014	E-mail: cmarak@littelfuse.com		
Category of Change:	Description of Change:		
☐ Assembly Process	Approve a new wafer foundry location and an alternate backend		
☐ Data Sheet	assembly, test, and packing location for SR70-02CTG product.		
☐ Technology	There are no changes to fit, form & function of the finished product. The		
☐ Discontinuance/Obsolescence			
☐ Equipment	affected products have been fully qualified in accordance with all established		
	criteria for performance and reliability		
☐ Raw Material	All relevant detail is included in the supplemental pages		
☐ Testing			
☐ Fabrication Process			
Other:			
Important Dates:			
Qualification Samples Available: 12/	19/2014		
☐ Final Qualification Data Available: 12	2/19/2014		
☐ Date of Final Product Shipment:			
Method of Distinguishing Changed Pro	oduct		
☐ Product Mark,			
☐ Date Code,			
	CN report for details		
Date Code,			
□ Date Code,☑ Other, See (8.0) in the succeeding Potential			
☐ Date Code, ☐ Other, See (8.0) in the succeeding PC Demonstrated or Anticipated Impact o			
☐ Date Code, ☐ Other, See (8.0) in the succeeding PC Demonstrated or Anticipated Impact o N/A			
□ Date Code, □ Other, See (8.0) in the succeeding PC Demonstrated or Anticipated Impact o N/A LF Qualification Plan/Results: N/A			
□ Date Code, □ Other, See (8.0) in the succeeding PC Demonstrated or Anticipated Impact o N/A LF Qualification Plan/Results: N/A Customer Acknowledgement of Recei	n Form, Fit, Function or Reliability:		



PCN Report ETR # 64833

Prepared By: Jordan Hsieh-SPA Product Engineering Manager,

: Ming-Huan Ko-SPA Product Engineer

Date : DEC/16/2014

Device : SR70-02CTG Product

Revision : A

1.0 Objective:

The purpose of this project is to qualify a new wafer foundry location and a second / alternate assembly location for SR70-02CTG product. Succeeding pages summarize the physical, electrical and reliability test performed in qualification lots.

2.0 Applicable Devices:

Part Numbers	Part Numbers
SR70-02CTG	

3.0 Assembly, Process & Material Differences/Changes:

3.1 Assembly and Process Changes

There are no changes in the assembly and process method.

3.2 Material Changes

	SR70-02CTG						
Material		ginal	New		CI 10		
	Material Name	Supplier	Material Name	Supplier	Changed?		
Leadframe	YEF-42	XMYH	A42	PSMC	Yes		
Die Attach Material	84-1LMISR4	HENKEL	84-1LMISR4	HENKEL	No		
Au Wire	30um	HERAEUS	30um	HERAEUS	No		
Molding Compound	ELER-8-100HFE	E'DALE	G600	SUMITOMO BAKELITE	Yes		
Lead Finish	Matte Tin	Yunnan	Matte Tin	REDRING SOLDER (M) SDN. BHD.	Yes		
Wafer	333DA		LFSPR03A LFSNR01A		Yes		

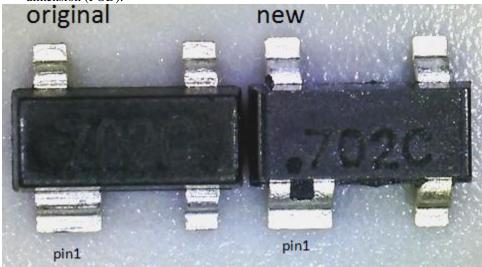
4.0 Packing Method

There will be no changes in the packing method.

5.0 Physical Differences/Changes:



Pin1 appearance is changed. The other dimensions are no change in mechanical specification or package outline dimension (POD).



6.0 Reliability Test Results Summary:

Test Items	Condition	S/S	Results	ETR#	
Precondition	Bake 24hr @ 150°C	320	0/320		
DC Blocking(HTRB)	Bias = 70V & 140V Ta = 125°C Duration = 1008 Hours	160 0/160			
Temperature Cycle	Ta = -55°C to +150°C Duration = 1000 Cycles	80	0/80		
Temperature/Humidity (H³TRB)	Bias=70V Ta = 85°C, 85% RH Duration = 1008 Hours	79	0/79	ETR 64833	
Autoclave	Ta = 121°C, 100%RH, 15psi 80 0/80 Duration = 96 Hours 80 0/80 Refer to Precondition Test 80 0/80		0/80		
Moisture Sensitivity Level(MSL)					
Mechanical Dimensions	Refer to spec in datasheet	30	0/30		

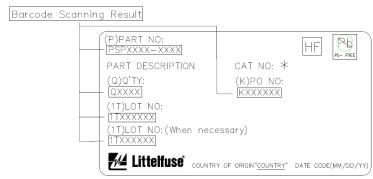
7.0 Electrical Characteristic Summary:

There is no change in electrical characteristics. Characterization data is available upon request.

8.0 Changed Part Identification:

To distinguish different manufacturing locations please refer to labeling information as CAT NO:





Original	New Backend	
	Location	
CAT No : S	CAT No : C	

9.0 Recommendations & Conclusions:

Based on the test results, it is determined that the new wafer foundry location and the second/alternative assembly location are qualified and certified for production of Littelfuse® SR70-02CTG product.

10.0 Approvals:

Jordan Hsieh SPA Product Engineering Manager Littelfuse, Hsinchu